Photocouplers GaA As Infrared LED & Photo IC

# TLP2403

- 1. Applications
- 2. General

#### 3. Features



Note: When an EN60747-5-2 approved type is needed, please designate the **Option (V4)**.



#### 4. Packaging and Pin Configuration

# 5. Internal Circuit



Fig. 5.1 Internal Circuit

# 6. Principle of Operation

# 6.1. Mechanical Parameters

Characteristics	Min	Unit
Creepage distances	4.0	mm
Clearance	4.0	
Internal isolation thickness	_	

#### 7. Absolute Maximum Ratings (Note)

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	Characteristics		Symbol	Note	Rating	Unit
LED	Forward current		١ <sub>F</sub>		20	mA
	Forward current derating	$(T_a \ge 85^{\circ}C)$	∆I <sub>F</sub> /°C		-0.67	mA/°C
	Pulse forward current		I <sub>FP</sub>	(Note 1)	40	mA
	Pulse forward current derating	$(T_a \ge 85^{\circ}C)$	∆l <sub>FP</sub> /°C		-1.0	mA/°C
	Transient pulse forward current		I <sub>FPT</sub>	(Note 2)	1	A
	Transient pulse forward current derating	$(T_a \ge 85^{\circ}C)$	∆I <sub>FPT</sub> /°C		-25	mA/°C
	Reverse voltage		V <sub>R</sub>		5	V
	Power dissipation		PD		40	mW
	Power dissipation derating	$(T_a \ge 85^{\circ}C)$	$\Delta P_D / C$		-1.0	mW/°C
Detector	Output current		Ι <sub>Ο</sub>		60	mA
	Output current derating	$(T_a \ge 25^{\circ}C)$	∆l <sub>O</sub> /°C		-0.6	mA/°C
	Output voltage		Vo		-0.5 to 18	V
	Supply voltage		V <sub>CC</sub>		-0.5 to 18	
	Emitter-base reverse voltage		V <sub>EB</sub>		0.5	
	Output power dissipation		Po		100	mW
	Output power dissipation derating	$(T_a \ge 25^{\circ}C)$	∆P <sub>O</sub> /°C		-1.0	mW/°C
Common	Operating temperature		T <sub>opr</sub>		-40 to 100	°C
	Storage temperature		T <sub>stg</sub>		-55 to 125	
	Lead soldering temperature	(10 s)	T <sub>sol</sub>		260	
	Isolation voltage	AC, 1 min, R.H. ≤ 60%	BVS	(Note 3)	3750	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Pulse width (PW)  $\leq$  1 ms, duty = 50%

Note 2: Pulse width (PW)  $\leq$  1  $\mu$ s, 300 pps

Note 3: This device is considered as a two-terminal device: Pins 1, 2, 3 and 4 are shorted together, and pins 5, 6, 7 and 8 are shorted together.

#### 8. Recommended Operating Conditions (Note)

Chara	acteristics	Symbol	Note	Min	Тур.	Max	Unit
Forward current		I <sub>F</sub>		0.5	—	15	mA
Output current		Ι <sub>Ο</sub>		—	—	30	
Supply voltage		V <sub>CC</sub>		_	_	16	
Operating temperature		T <sub>opr</sub>	(Note 1)	-40	_	100	

# 9. Electrical Characteristics (Note)

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Characteristics	Symbol	Note	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input forward voltage	V <sub>F</sub>			I <sub>F</sub> = 1.6 mA, T <sub>a</sub> = 25°C	1.30	1.45	1.70	V
Input temperature coefficient of forward voltage	$\Delta V_{F} / \Delta T_{a}$			I <sub>F</sub> = 1.6 mA	_	-1.8	—	mV/°C
Input reverse current	I <sub>R</sub>			V <sub>R</sub> = 5 V, T <sub>a</sub> = 25°C	_		10	μA
Input capacitance	Ct			$V = 0 V, f = 1 MHz, T_a = 25^{\circ}C$	_	60	_	pF
High-level output current	I <sub>OH</sub>			$V_F = 0.8 \text{ V}, V_{CC} = V_O = 18 \text{ V}$	_	0.1	100	μA
High-level supply current	I <sub>ССН</sub>			$I_{F} = 0 \text{ mA}, V_{CC} = 5 \text{ V}, \\ V_{O} = \text{Open}$	_	0.01	10	μA
Low-level supply current	I <sub>CCL</sub>			$I_{F} = 1.6 \text{ mA}, V_{CC} = 5 \text{ V}, \\ V_{O} = \text{Open}$	0.1	1	1.5	mA
Current transfer ratio	I <sub>O</sub> /I <sub>F</sub>			$ I_{\rm F} = 0.5 \mbox{ mA}, \mbox{ V}_{\rm CC} = 4.5 \mbox{ V}, \\ \mbox{ V}_{\rm O} = 0.4 \mbox{ V} $	400	1000	—	%
				$I_{\rm F} = 1.6 \text{ mA}, V_{\rm CC} = 4.5 \text{ V}, \\ V_{\rm O} = 0.4 \text{ V}$	500	900	_	
Low-level output voltage	V <sub>OL</sub>			$I_F = 1.6 \text{ mA}, V_{CC} = 4.5 \text{ V},$ $I_{OL} = 6.4 \text{ mA}$		0.1	0.4	V
				$I_{F} = 5 \text{ mA}, V_{CC} = 4.5 \text{ V},$ $I_{OL} = 15 \text{ mA}$	_	0.1	0.4	
				$I_F = 12 \text{ mA}, V_{CC} = 4.5 \text{ V},$ $V_O = 24 \text{ mA}$	_	0.15	0.4	

Note: All typical values are at  $T_a = 25^{\circ}C$ .

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#### **10. Isolation Characteristics**

Characteristics	Symbol	Note	Test Conditions	Min	Тур.	Max	Unit
Capacitance (input to output)	Cs	(Note 1)	$V_{S} = 0 V, f = 1 MHz$	_	0.8		pF
Isolation resistance	R <sub>S</sub>	(Note 1)	$V_{S} = 500 \text{ V}, \text{ R.H.} \le 60\%$	1×10 <sup>12</sup>	1014	_	Ω
Isolation voltage	BVS		AC, 1 min	3750			Vrms
			AC, 1 s in oil	_	10000	_	
			DC, 1 min in oil	_	10000	_	Vdc

Note 1: This device is considered as a two-terminal device: Pins 1, 2, 3 and 4 are shorted together, and pins 5, 6, 7 and 8 are shorted together.



# **11. Switching Characteristics**

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Characteristics	Symbol	Note	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Propagation delay time (H/L)	t <sub>pHL</sub>		Fig. 12.1.1	I <sub>F</sub> = 0.5 mA, R <sub>L</sub> = 4.7 kΩ, T <sub>a</sub> = 25°C	—	2	25	μs
				$I_F = 0.5 \text{ mA}, R_L = 4.7 \text{ k}\Omega$	_	2	30	
				$I_F = 12 \text{ mA}, \text{ R}_L = 270 \Omega,$ T <sub>a</sub> = 25°C	—	0.3	1	
				$I_F$ = 12 mA, $R_L$ = 270 $\Omega$	_	0.3	2	
				$I_F$ = 1.6 mA, R <sub>L</sub> = 2.2 kΩ, T <sub>a</sub> = 25°C	—	0.5	10	
				$I_F$ = 1.6 mA, $R_L$ = 2.2 k $\Omega$	_	0.5	15	
Propagation delay time (L/H)	t <sub>pLH</sub>		Fig. 12.1.1	I <sub>F</sub> = 0.5 mA, R <sub>L</sub> = 4.7 kΩ, T <sub>a</sub> = 25°C	—	4	60	μs
				$I_F = 0.5 \text{ mA}, R_L = 4.7 \text{ k}\Omega$	_	4	90	
				$I_F = 12 \text{ mA}, \text{ R}_L = 270 \Omega,$ $T_a = 25^{\circ}\text{C}$	—	1	7	
				$I_F$ = 12 mA, $R_L$ = 270 $\Omega$	_	1	10	
				$I_F = 1.6 \text{ mA}, \text{ R}_L = 2.2 \text{ k}\Omega,$ $T_a = 25^{\circ}\text{C}$	—	4.5	35	
				$I_F$ = 1.6 mA, $R_L$ = 2.2 k $\Omega$		4.5	50	
Common-mode transient immunity at output high	CM <sub>H</sub>	(Note 1)	Fig. 12.1.2	$\begin{split} I_{F} &= 0 \text{ mA}, \text{ R}_{L} = 2.2 \text{ k}\Omega, \\ V_{CM} &= 10 \text{ V}, \text{ V}_{O(min)} = 2 \text{ V} \end{split}$	_	500	_	V/µs
Common-mode transient immunity at output low	$CM_L$	(Note 2)		$I_F$ = 1.6 mA, R <sub>L</sub> = 2.2 kΩ, V <sub>CM</sub> = 10 V, V <sub>O(max)</sub> = 0.8 V	_	-500	—	

#### 12. Test Circuits and Characteristics Curves

# 12.1. Test Circuits



Fig. 12.1.2 Common-Mode Transient Immunity

# 13. Soldering and Storage

# 13.1. Precautions for Soldering





Fig. 13.1.2 An example of a temperature profile

when lead(Pb)-free solder is used

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Fig. 13.1.1 An example of a temperature profile when Sn-Pb eutectic solder is used



13.2. Precautions for General Storage



# 14. Land Pattern Dimensions for Reference Only



Fig. 14.1 Land Pattern Dimensions for Reference Only (unit: mm)

# 15. Marking



Fig. 15.1 Marking



Minimum creepage distance	Cr	4.0mm
Minimum clearance	CI	4.0mm
Minimum in a dation dried		



- Note: If a printed circuit is incorporated, the creepage distance and clearance may be reduced below this value. (e. g., at a standard distance between soldering eye centers of 3.5 mm). If this is not permissible, the user shall take suitable measures.
- Note: This photocoupler is suitable for **safe electrical isolation** only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits.



#### Fig. 16.3 Marking Example (Note)

Note: The above marking is applied to the photocouplers that have been qualified according to option (V4) of EN60747.

# TLP2403

# Package Dimensions

Unit: mm



Weight: 0.11 g (typ.)

Package Name(s) TOSHIBA: 11-5K1S Nickname: SO8

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